9-bit odd/even parity generator/checker 74F280B

FEATURES

- High-impedance NPN base inputs for reduced loading (20μA in Low and High states)
- Buffered inputs — one normalized load
- Word length easily expanded by cascading
- Industrial temperature range available (–40°C to +85°C)

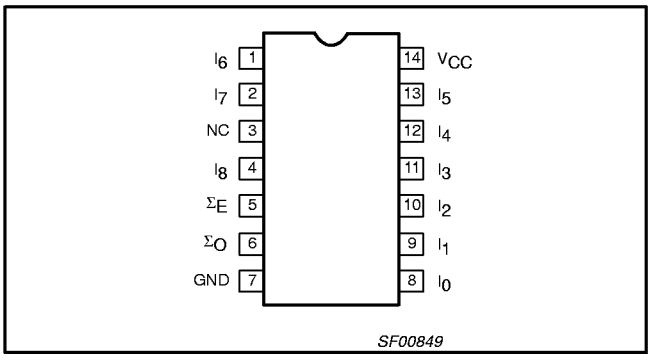
DESCRIPTION

The 74F280B is a 9-bit Parity Generator or Checker commonly used to detect errors in high speed data transmission or data retrieval systems. Both Even (Σ_E) and Odd (Σ_O) parity outputs are available for generating or checking even or odd parity on up to 9 bits.

The Even (Σ_E) parity output is High when an even number of Data inputs (I_0 - I_8) are High. The Odd (Σ_O) parity output is High when an odd number of Data inputs are High.

Expansion to larger word sizes is accomplished by tying the Even (Σ_E) outputs of up to nine parallel devices to the data inputs of the final stage. This expansion scheme allows an 81-bit data word to be checked in less than 20ns.

PIN CONFIGURATION



TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F280B	5.5ns	26mA

ORDERING INFORMATION

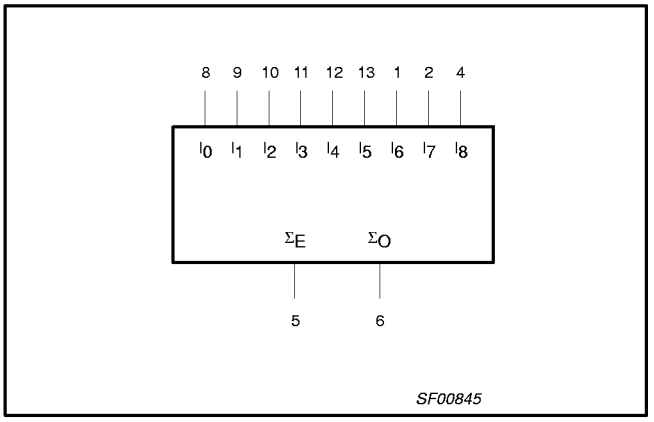
DESCRIPTION	COMMERCIAL RANGE V_{CC} = 5V ±10%, T_{amb} = 0°C to +70°C	INDUSTRIAL RANGE V_{CC} = 5V ±10%, T_{amb} = –40°C to +85°C	PKG. DWG. #
14-pin plastic DIP	N74F280BN	I74F280BN	SOT27-1
14-pin plastic SO	N74F280BD	I74F280BD	SOT108-1

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

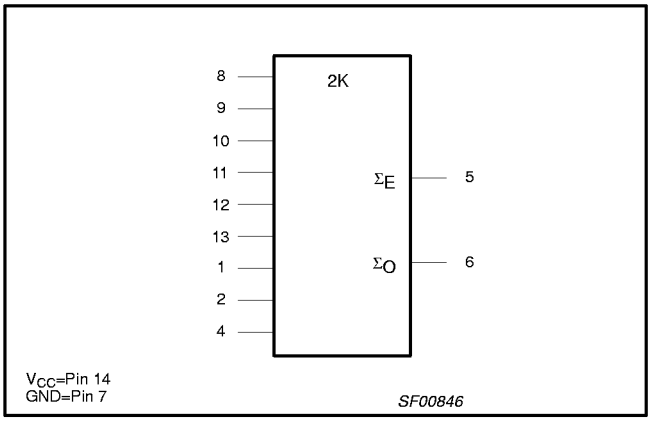
PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
I_0 - I_8	Data inputs	1.0/0.033	20μA/20μA
Σ_E, Σ_O	Parity outputs	50/33	1.0mA/20mA

NOTE:
One (1.0) FAST Unit Load is defined as: 20μA in the High state and 0.6mA in the Low state.

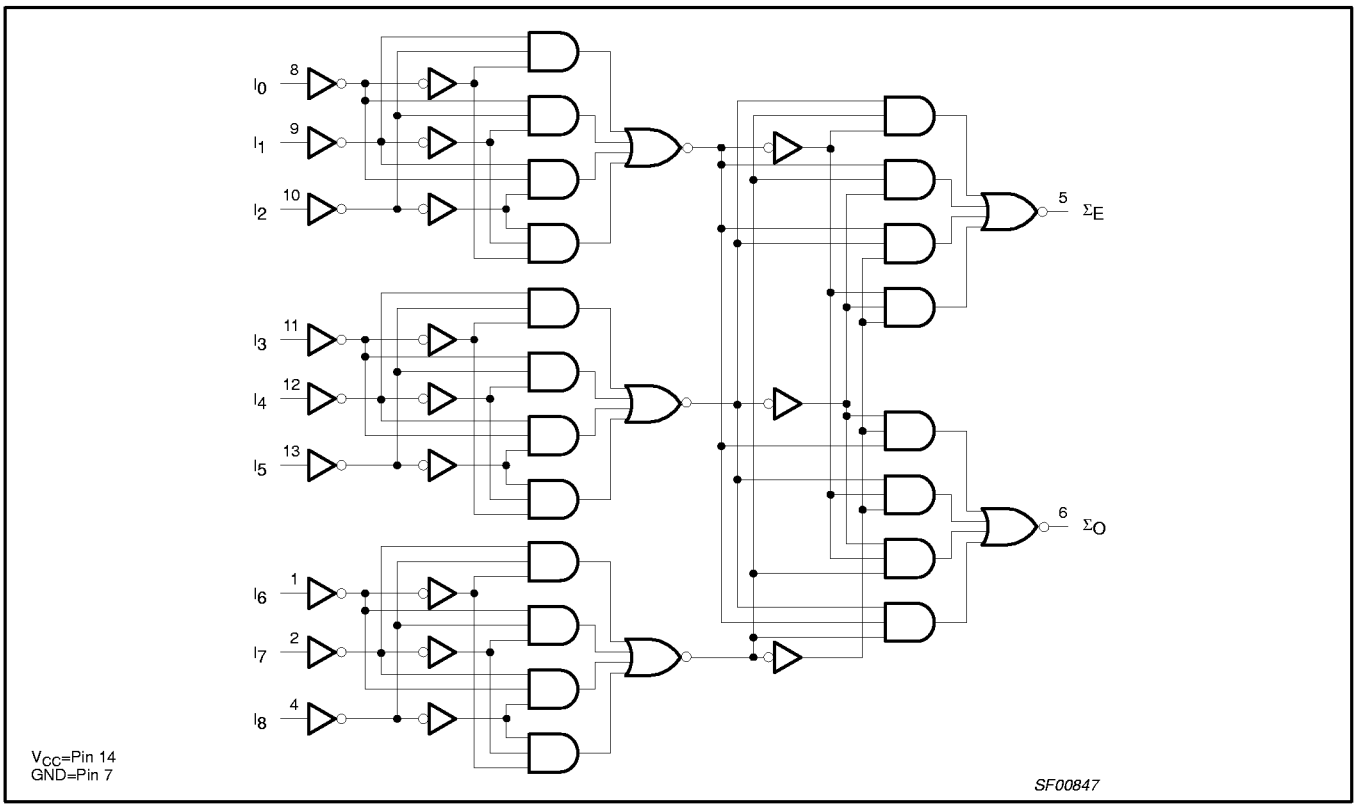
LOGIC SYMBOL



IEC/IEEE SYMBOL



LOGIC DIAGRAM



FUNCTION TABLE

INPUTS	OUTPUTS	
Number of High Data Inputs (I_0 - I_8)	Σ_E	Σ_O
Even — 0, 2, 4, 6, 8	H	L
Odd — 1, 3, 5, 7, 9	L	H

H = High voltage level
L = Low voltage level

ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER		RATING	UNIT
V_{CC}	Supply voltage		–0.5 to +7.0	V
V_{IN}	Input voltage		–0.5 to +7.0	V
I_{IN}	Input current		–30 to +5	mA
V_{OUT}	Voltage applied to output in High output state		–0.5 to V_{CC}	V
I_{OUT}	Current applied to output in Low output state		40	mA
T_{amb}	Operating free-air temperature range	Commercial range	0 to +70	°C
		Industrial range	–40 to +85	°C
T_{stg}	Storage temperature		–65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER		LIMITS			UNIT
			Min	Nom	Max	
V_{CC}	Supply voltage		4.5	5.0	5.5	V
V_{IH}	High-level input voltage		2.0			V
V_{IL}	Low-level input voltage				0.8	V
I_{IK}	Input clamp current				–18	mA
I_{OH}	High-level output current				–1	mA
I_{OL}	Low-level output current				20	mA
T_{amb}	Operating free-air temperature range	Commercial range	0		70	°C
		Industrial range	–40		85	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIONS[NO TAG]		LIMITS			UNIT
					MIN	TYP NO TAG	MAX	
V_{OH}	High-level output voltage		V_{CC} = MIN, V_{IL} = MAX	±10%V_{CC}	2.5			V
			V_{IH} = MIN, I_{OH} = MAX	±5%V_{CC}	2.7	3.4		
V_{OL}	Low-level output voltage		V_{CC} = MIN, V_{IL} = MAX	±10%V_{CC}		0.35	0.50	V
			V_{IH} = MIN, I_{OL} = MAX	±5%V_{CC}		0.35	0.50	
V_{IK}	Input clamp voltage		V_{CC} = MIN, I_I = I_{IK}			–0.73	–1.2	V
I_I	Input current at maximum input voltage		V_{CC} = 0.0V, V_I = 7.0V				100	µA
I_{IH}	High-level input current	Commercial range	V_{CC} = MAX, V_I = 2.7V				20	µA
		Industrial range					40	µA
I_{IL}	Low-level input current		V_{CC} = MAX, V_I = 0.5V				–20	µA
I_{OS}	Short-circuit output current[NO TAG]		V_{CC} = MAX		–60		–150	mA
I_{CC}	Supply current (total)		V_{CC} = MAX			26	35	mA

NOTES:

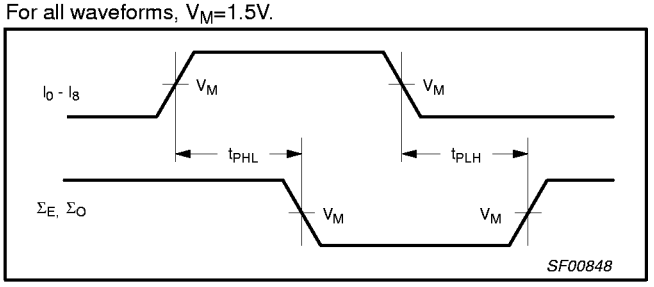
1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
2. All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

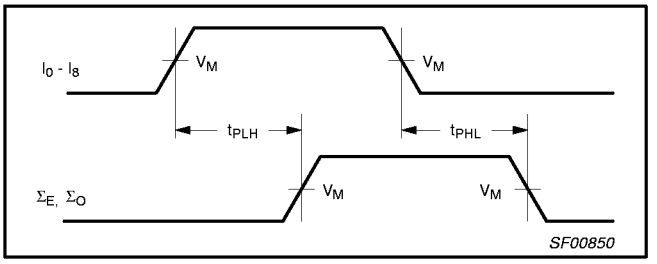
SYMBOL	PARAMETER		TEST CONDITIONS	LIMITS							UNIT
				T_{amb}= +25°C V_{CC} = +5.V C_L = 50pF, R_L = 500Ω			T_{amb} = 0°C to +70°C V_{CC} = +5.V ± 10% C_L = 50pF, R_L = 500Ω		T_{amb} = -40°C to +85°C V_{CC} = +5.V ± 10% C_L = 50pF, R_L = 500Ω		
				Min	Typ	Max	Min	Max	Min	Max	
t_{PLH} t_{PHL}	Propagation delay I_0 - I_8 to Σ_E	74F280B	Waveform 1, 2	4.0 4.0	6.5 7.0	9.0 10.0	3.5 3.5	10.0 11.1	3.0 3.5	11.0 12.0	ns ns
t_{PLH} t_{PHL}	Propagation delay I_0 - I_8 to Σ_O		Waveform 1, 2	4.0 4.0	6.5 7.0	9.0 10.0	3.5 3.5	10.0 11.0	3.0 3.5	11.0 12.0	ns ns

AC WAVEFORMS

For all waveforms, V_M=1.5V.

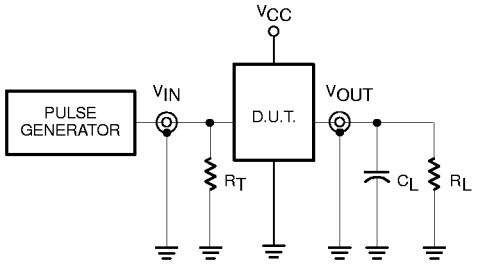


Waveform 1. Propagation Delay for Inverting Outputs

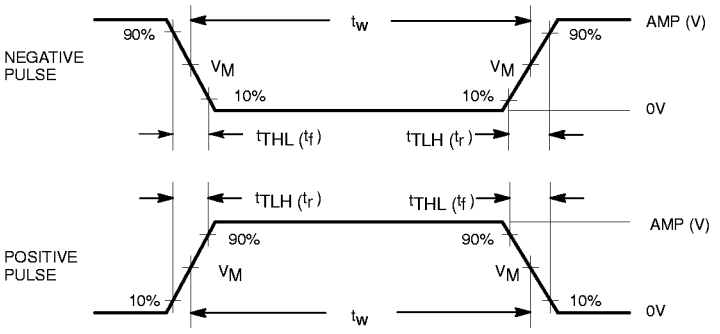


Waveform 2. Propagation Delay for Non-Inverting Outputs

TEST CIRCUIT AND WAVEFORM



Test Circuit for Totem-Pole Outputs



DEFINITIONS:

R_L = Load resistor; see AC ELECTRICAL CHARACTERISTICS for value.

C_L = Load capacitance includes jig and probe capacitance; see AC ELECTRICAL CHARACTERISTICS for value.

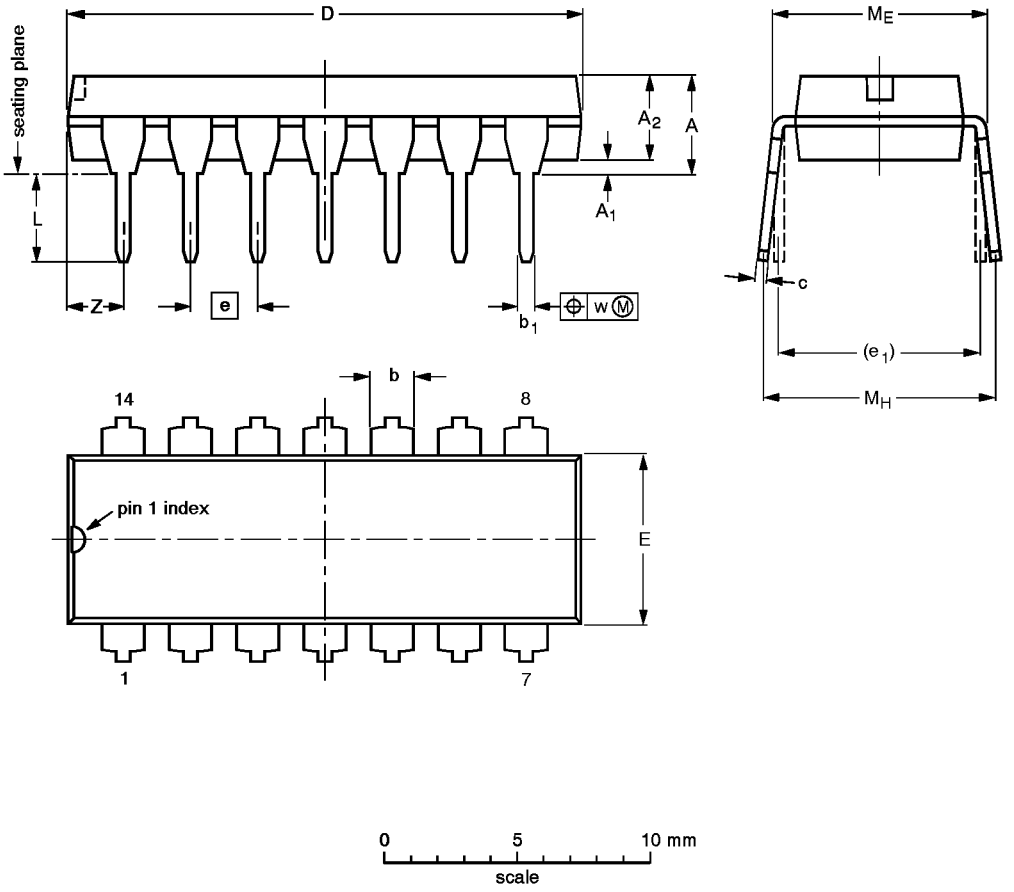
R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

Input Pulse Definition

family	INPUT PULSE REQUIREMENTS					
	amplitude	V_M	rep. rate	t_w	t_{TLH}	t_{THL}
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns

SF00006

DIP14: plastic dual in-line package; 14 leads (300 mil) SOT27-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

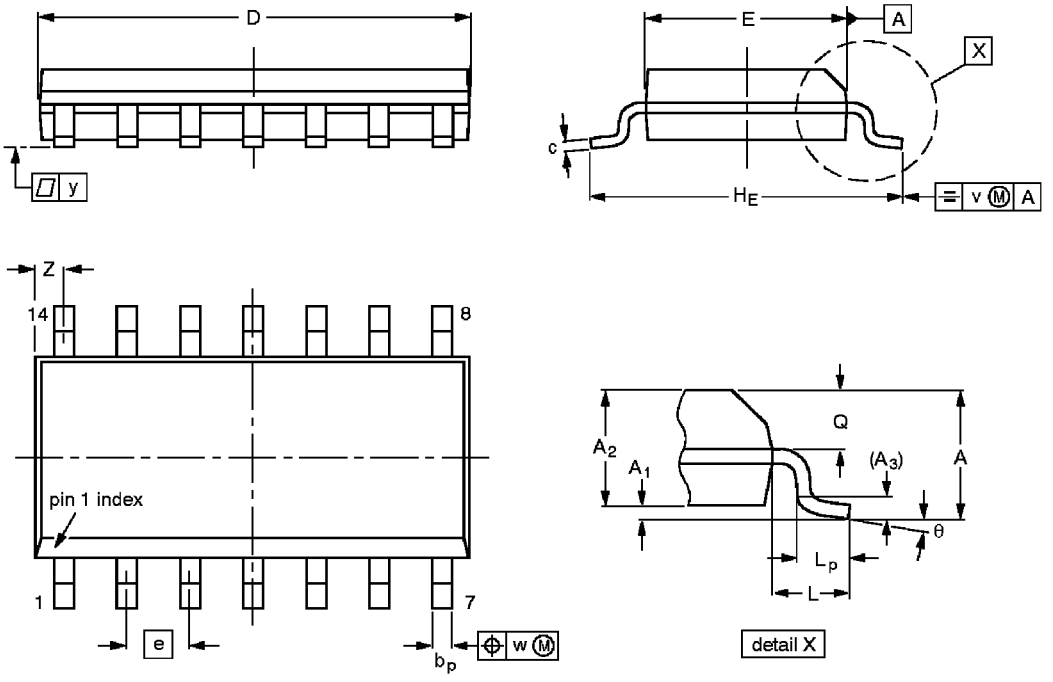
UNIT	A max.	A_1 min.	A_2 max.	b	b_1	c	D (1)	E (1)	e	e_1	L	M_E	M_H	w	Z (1) max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.020	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

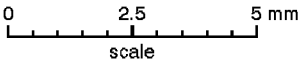
Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT27-1	050G04	MO-001AA				~~92-11-17~~ 95-03-11

SO14: plastic small outline package; 14 leads; body width 3.9 mm SOT108-1





DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A_1	A_2	A_3	b_p	c	$D^{(1)}$	$E^{(1)}$	e	H_E	L	L_p	Q	v	w	y	$Z^{(1)}$	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8° 0°
inches	0.069	0.010 0.004	0.057 0.049	0.01	0.019 0.014	0.0100 0.0075	0.35 0.34	0.16 0.15	0.050	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT108-1	076E06S	MS-012AB				~~95-01-23~~ 97-05-22

Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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